

WHAT IS CLAIMED IS:

1. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:

5 a microscope, including at least one objective lens and a base;
 a defect marker fixed to said base, wherein said defect marker locates a defect.

2. The defect identifying apparatus of claim 1, wherein said defect
10 marker further includes a marking tip positioned between said objective lens and a focal plane of said objective lens.

3. The defect identifying apparatus of claim 1, wherein said defect
marker further includes an ink jet.

15 4. A defect identifying apparatus, for inspecting and locating defects on an LCD substrate, said defect identifying apparatus comprising:

 an inspection apparatus, including a base;
 a defect marker fixed to said base, said defect marker including an ink jet,
20 wherein said ink jet marks a defect.

5. The defect identifying apparatus of claim 4, wherein said inspection apparatus is a microscope.

6. The defect identifying apparatus of claim 5, wherein said microscope further includes an objective lens.

7. The defect identifying apparatus of claim 6, wherein said ink jet is
5 positioned between said objective lens and a focal plane of said objective lens.